Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/790,871	TATEIWA, AKIHIKO
Examiner	Art Unit

James D. Stein

2874

SEARCHED					
Class	Subclass	Date	Examiner		
385	27,31,39, 42,49,50, 51,78,95	6/15/2005	JDS		
385	124	6/15/2005	JDS		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		-			
	<u></u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
DATE	EXMR			
6/15/2005	JDS			
6/15/200 <u>5</u>	JDS			
	DATE 6/15/2005			